



## Description

### JMT N And P-Channel Enhancement Mode MOSFET

#### Features

- N-Channel: 40V, 16A  
 $R_{DS(ON)} < 22m\Omega @ V_{GS} = -10V$   
 $R_{DS(ON)} < 31m\Omega @ V_{GS} = -4.5V$
- P-Channel: -40V, -16A  
 $R_{DS(ON)} < 52m\Omega @ V_{GS} = -10V$   
 $R_{DS(ON)} < 70m\Omega @ V_{GS} = -4.5V$
- Excellent Gate Charge x  $R_{DS(ON)}$  Product(FOM)
- Very Low On-resistance  $R_{DS(ON)}$
- Fast Switching Speed

#### Application

- Battery Protection
- Load Switch
- Power Management



**100% UIS TESTED!**  
**100% ΔVds TESTED!**

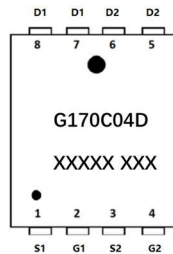


Top View

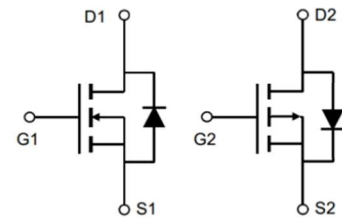


Bottom View

PDFN5X6-8L



Marking and pin Assignment



Schematic Diagram

## Package Marking and Ordering Information

Device Marking	Device	OUTLINE	Device Package	Reel Size	Reel (PCS)	Per Carton (PCS)
G170C04D	JMTG170C04D	TAPING	PDFN5X6-8L	13inch	5000	-

## Absolute Maximum Ratings (T<sub>C</sub>=25°C unless otherwise specified)

Symbol	Parameter	Max. N-Channel	Max. P-Channel	Units
V <sub>DSS</sub>	Drain-Source Voltage	40	-40	V
V <sub>GSS</sub>	Gate-Source Voltage	±20	±20	V
I <sub>D</sub>	Continuous Drain Current	T <sub>C</sub> = 25°C	-16	A
		T <sub>C</sub> = 100°C	-10	A
I <sub>DM</sub>	Pulsed Drain Current <sup>note1</sup>	64	-64	A
E <sub>AS</sub>	Single Pulsed Avalanche Energy <sup>note2</sup>	19	27.5	mJ
P <sub>D</sub>	Power Dissipation	T <sub>C</sub> = 25°C	22	W
R <sub>θJA</sub>	Thermal Resistance, Junction to Case	13	5.7	°C/W
T <sub>J</sub> , T <sub>STG</sub>	Operating and Storage Temperature Range	-55 to +150		°C



## N-Channel Electrical Characteristics (T<sub>J</sub>=25°C unless otherwise specified)

Symbol	Parameter	Test Condition	Min.	Typ.	Max.	Units
<b>Off Characteristic</b>						
V <sub>(BR)DSS</sub>	Drain-Source Breakdown Voltage	V <sub>GS</sub> =0V, I <sub>D</sub> =250μA	40	-	-	V
I <sub>DSS</sub>	Zero Gate Voltage Drain Current	V <sub>DS</sub> =40V, V <sub>GS</sub> =0V	-	-	1.0	μA
I <sub>GSS</sub>	Gate to Body Leakage Current	V <sub>DS</sub> =0V, V <sub>GS</sub> =±20V	-	-	±100	nA
<b>On Characteristics</b>						
V <sub>GS(th)</sub>	Gate Threshold Voltage	V <sub>DS</sub> =V <sub>GS</sub> , I <sub>D</sub> =250μA	1.0	1.5	2.5	V
R <sub>DS(on)</sub>	Static Drain-Source on-Resistance <small>note3</small>	V <sub>GS</sub> =10V, I <sub>D</sub> =15A	-	16	22	mΩ
		V <sub>GS</sub> =4.5V, I <sub>D</sub> =10A	-	22	31	mΩ
<b>Dynamic Characteristics</b>						
C <sub>iss</sub>	Input Capacitance	V <sub>DS</sub> =20V, V <sub>GS</sub> =0V, f=1.0MHz	-	980	-	pF
C <sub>oss</sub>	Output Capacitance		-	86.2	-	pF
C <sub>rss</sub>	Reverse Transfer Capacitance		-	68.5	-	pF
Q <sub>g</sub>	Total Gate Charge	V <sub>DS</sub> =20V, I <sub>D</sub> =8A, V <sub>GS</sub> =10V	-	11	-	nC
Q <sub>gs</sub>	Gate-Source Charge		-	1.9	-	nC
Q <sub>gd</sub>	Gate-Drain("Miller") Charge		-	2.2	-	nC
<b>Switching Characteristics</b>						
t <sub>d(on)</sub>	Turn-on Delay Time	V <sub>DS</sub> =20V, I <sub>D</sub> = 16A, R <sub>L</sub> =2.5Ω, R <sub>REN</sub> =3Ω	-	11	-	ns
t <sub>r</sub>	Turn-on Rise Time		-	13	-	ns
t <sub>d(off)</sub>	Turn-off Delay Time		-	36	-	ns
t <sub>f</sub>	Turn-off Fall Time		-	9	-	ns
<b>Drain-Source Diode Characteristics and Maximum Ratings</b>						
I <sub>S</sub>	Maximum Continuous Drain to Source Diode Forward Current		-	-	16	A
I <sub>SM</sub>	Maximum Pulsed Drain to Source Diode Forward Current		-	-	64	A
V <sub>SD</sub>	Drain to Source Diode Forward Voltage	V <sub>GS</sub> =0V, I <sub>S</sub> = 16A	-	-0.8	-1.2	V
t <sub>rr</sub>	Body Diode Reverse Recovery Time	T <sub>J</sub> =25°C,	-	19	-	ns
Q <sub>rr</sub>	Body Diode Reverse Recovery	I <sub>F</sub> =16A, di/dt=100A/μs	-	11	-	nC

Notes:1. Repetitive Rating: Pulse Width Limited by Maximum Junction Temperature

2. EAS condition : T<sub>J</sub>=25°C, V<sub>DD</sub>=30V, V<sub>G</sub>=10V, L=0.5mH, R<sub>g</sub>=25Ω, I<sub>AS</sub>=8.7A

T<sub>J</sub>=25°C, V<sub>DD</sub>=-30V, V<sub>G</sub>= -10V, L=0.5mH, R<sub>g</sub>=25Ω, I<sub>AS</sub>= -10.5A

3. Pulse Test: Pulse Width≤300μs, Duty Cycle≤2%



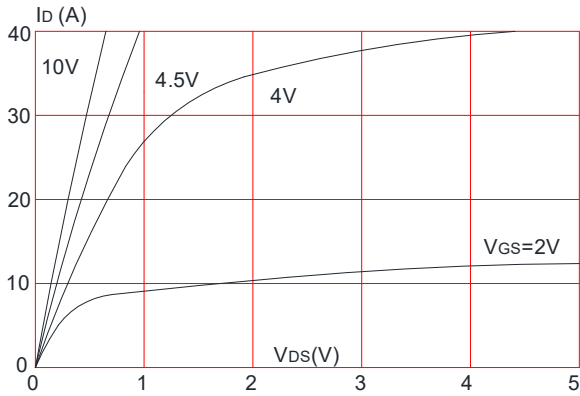
## P-Channel Electrical Characteristics (T<sub>J</sub>=25°C unless otherwise specified)

Symbol	Parameter	Test Condition	Min.	Typ.	Max.	Units
<b>Off Characteristic</b>						
V <sub>(BR)DSS</sub>	Drain-Source Breakdown Voltage	V <sub>GS</sub> =0V, I <sub>D</sub> = -250μA	-40	-	-	V
I <sub>DSS</sub>	Zero Gate Voltage Drain Current	V <sub>DS</sub> = -40V, V <sub>GS</sub> =0V	-	-	-1	μA
I <sub>GSS</sub>	Gate to Body Leakage Current	V <sub>DS</sub> =0V, V <sub>GS</sub> = ±20V	-	-	±100	nA
<b>On Characteristics</b>						
V <sub>GS(th)</sub>	Gate Threshold Voltage	V <sub>DS</sub> =V <sub>GS</sub> , I <sub>D</sub> = -250μA	-1.0	-1.6	-2.5	V
R <sub>DS(on)</sub>	Static Drain-Source on-Resistance <small>note3</small>	V <sub>GS</sub> = -10V, I <sub>D</sub> = -8A	-	40	52	mΩ
		V <sub>GS</sub> = -4.5V, I <sub>D</sub> = -5A	-	50	70	
<b>Dynamic Characteristics</b>						
C <sub>iss</sub>	Input Capacitance	V <sub>DS</sub> = -20V, V <sub>GS</sub> =0V, f=1.0MHz	-	1034	-	pF
C <sub>oss</sub>	Output Capacitance		-	107	-	pF
C <sub>rss</sub>	Reverse Transfer Capacitance		-	79.5	-	pF
Q <sub>g</sub>	Total Gate Charge	V <sub>DS</sub> = -20V, I <sub>D</sub> = -8A, V <sub>GS</sub> = -10V	-	20	-	nC
Q <sub>gs</sub>	Gate-Source Charge		-	3.5	-	nC
Q <sub>gd</sub>	Gate-Drain("Miller") Charge		-	4.2	-	nC
<b>Switching Characteristics</b>						
t <sub>d(on)</sub>	Turn-on Delay Time	V <sub>DD</sub> = -20V, I <sub>D</sub> = -16A, V <sub>GS</sub> = -10V, R <sub>GEN</sub> =2.5Ω	-	8	-	ns
t <sub>r</sub>	Turn-on Rise Time		-	15	-	ns
t <sub>d(off)</sub>	Turn-off Delay Time		-	23	-	ns
t <sub>f</sub>	Turn-off Fall Time		-	9	-	ns
<b>Drain-Source Diode Characteristics and Maximum Ratings</b>						
I <sub>S</sub>	Maximum Continuous Drain to Source Diode Forward Current		-	-	-16	A
I <sub>SM</sub>	Maximum Pulsed Drain to Source Diode Forward Current		-	-	-64	A
V <sub>SD</sub>	Drain to Source Diode Forward Voltage	V <sub>GS</sub> =0V, I <sub>S</sub> = -16A	-	-0.8	-1.2	V
t <sub>rr</sub>	Reverse Recovery Time	V <sub>GS</sub> =0V, I <sub>S</sub> =-16A, di/dt=100A/μs	-	29	-	ns
Q <sub>rr</sub>	Reverse Recovery Charge		-	20	-	nC

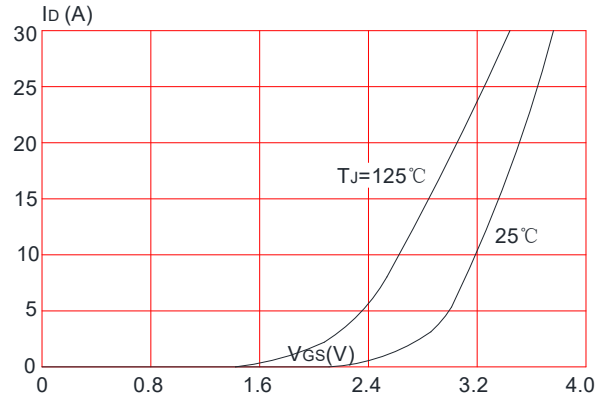


## Typical Performance Characteristics-N

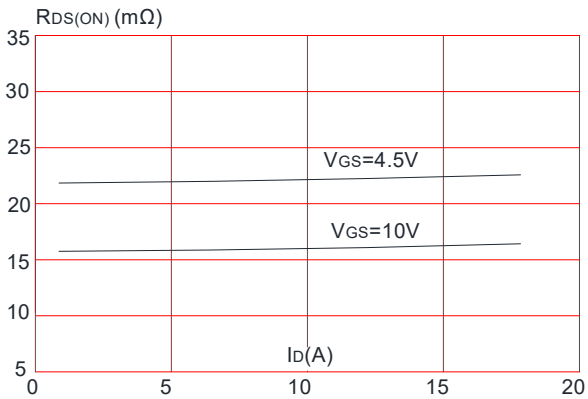
**Figure 1:** Output Characteristics



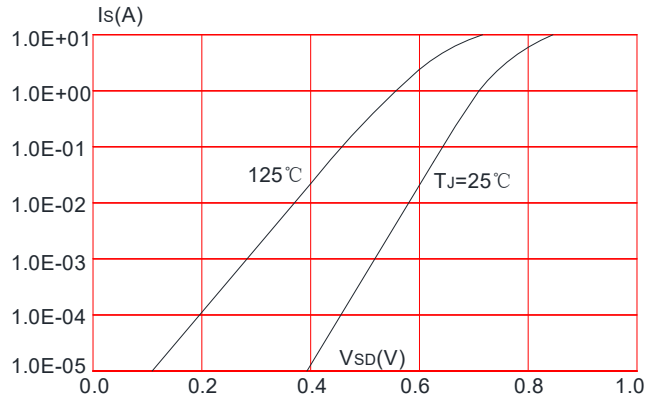
**Figure 2:** Typical Transfer Characteristics



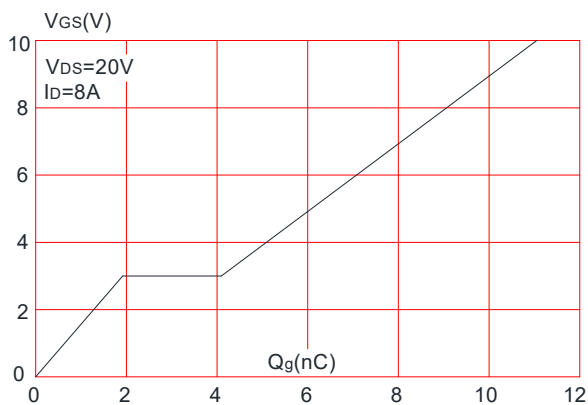
**Figure 3:** On-resistance vs. Drain Current



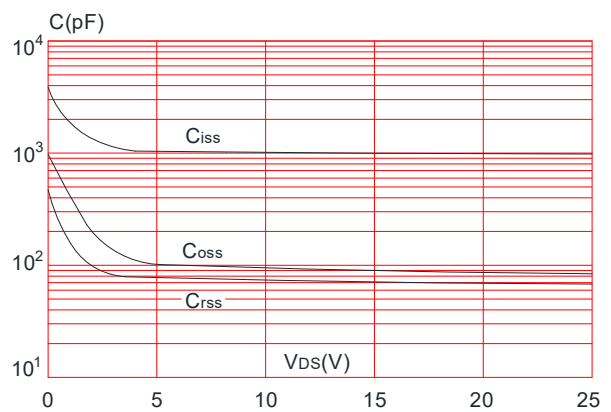
**Figure 4:** Body Diode Characteristics



**Figure 5:** Gate Charge Characteristics

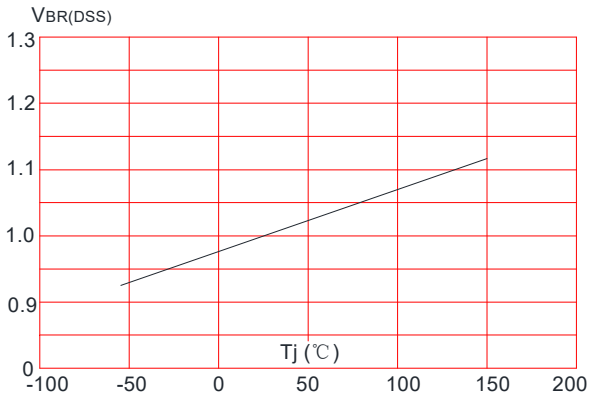


**Figure 6:** Capacitance Characteristics

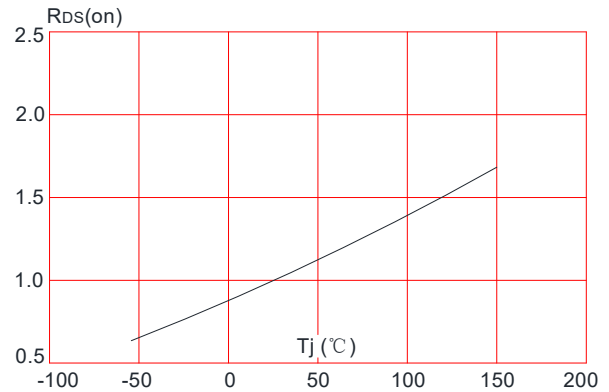




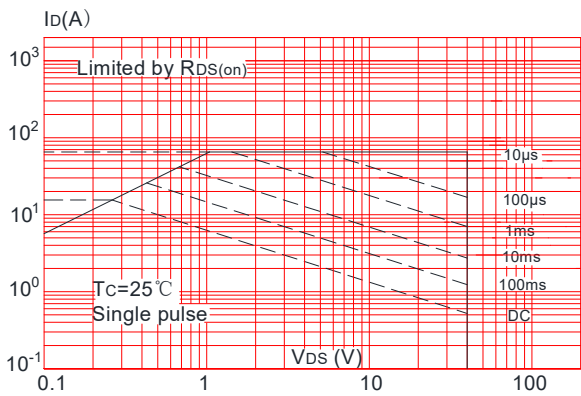
**Figure 7:** Normalized Breakdown Voltage vs. Junction Temperature



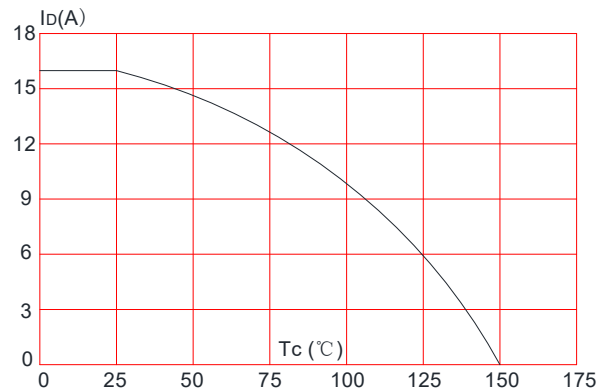
**Figure 8:** Normalized on Resistance vs. Junction Temperature



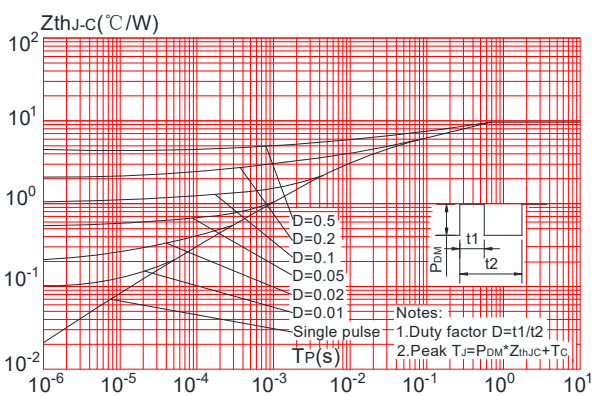
**Figure 9:** Maximum Safe Operating Area



**Figure 10:** Maximum Continuous Drain Current vs. Case Temperature



**Figure.11:** Maximum Effective Transient Thermal Impedance, Junction-to-Case



## Test Circuit-N

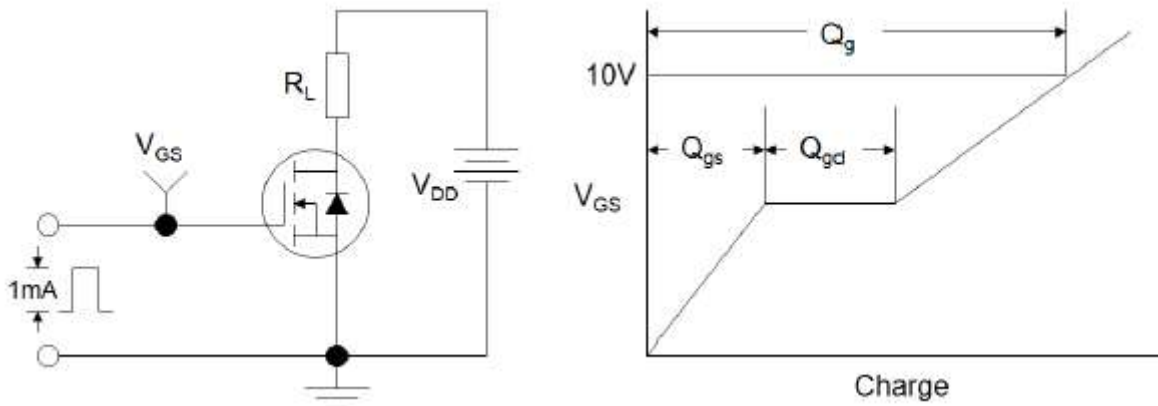


Figure1:Gate Charge Test Circuit & Waveform

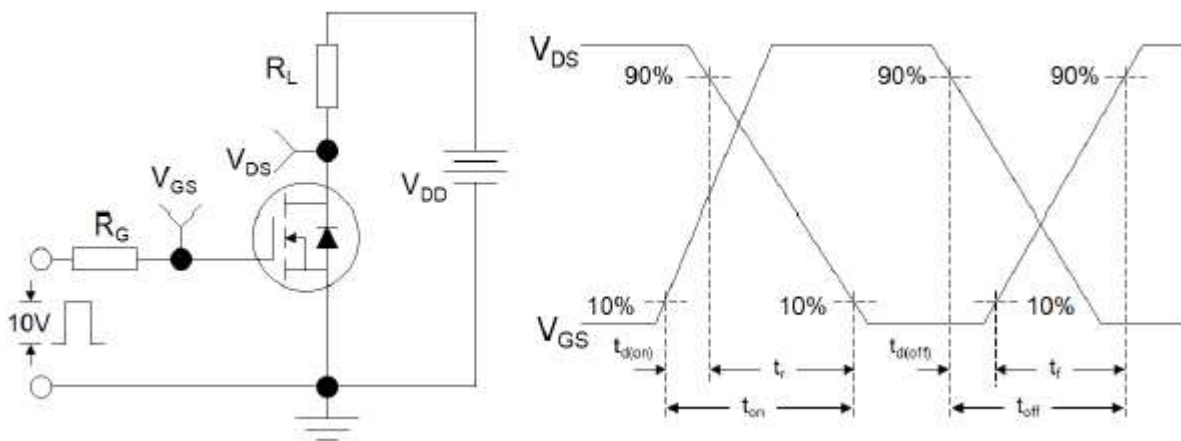


Figure 2: Resistive Switching Test Circuit & Waveforms

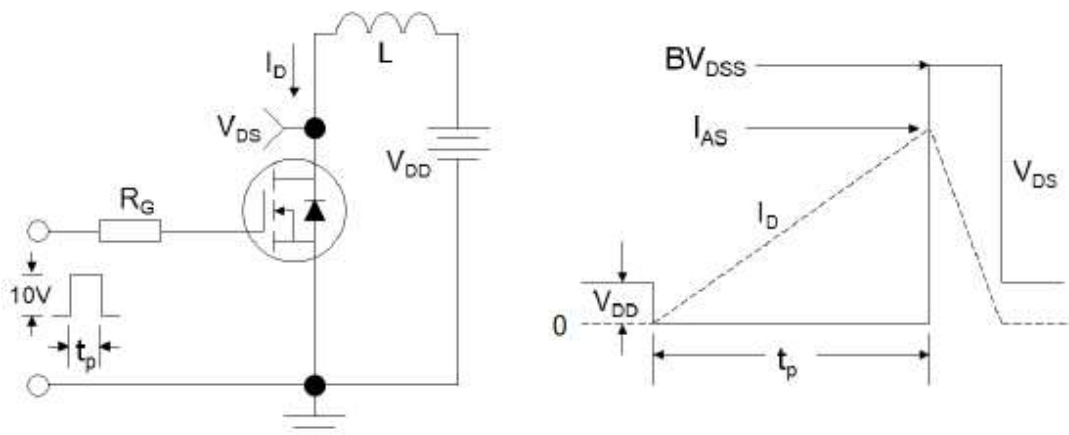
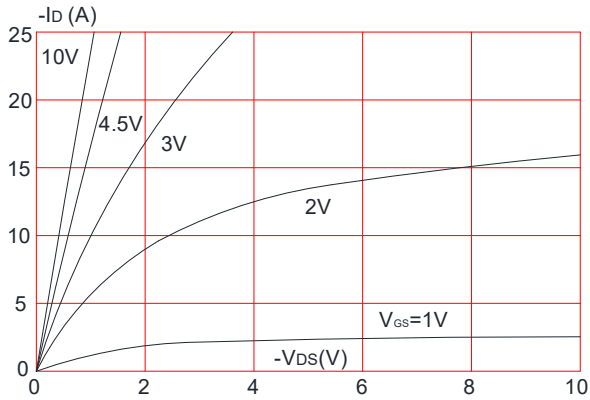


Figure 3:Unclamped Inductive Switching Test Circuit & Waveforms

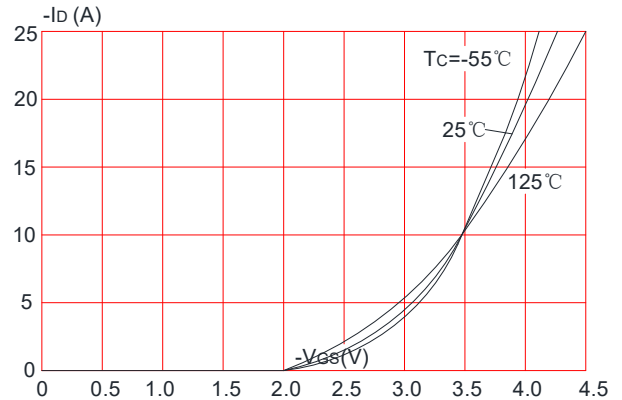


## Typical Performance Characteristics-P

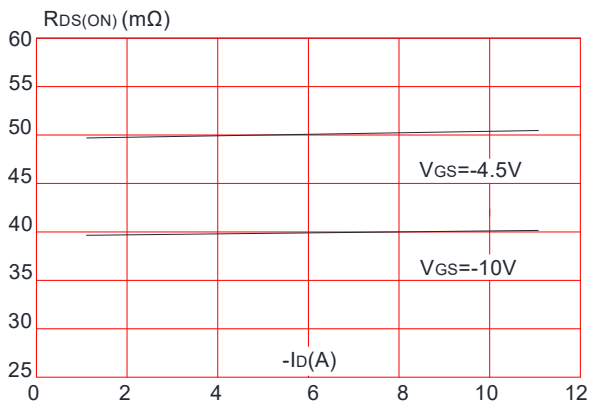
**Figure 1:** Output Characteristics



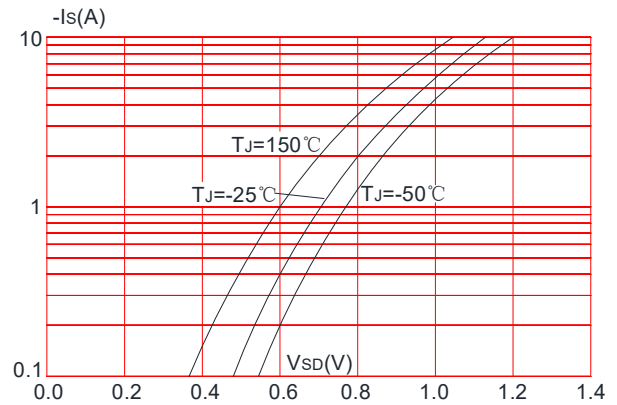
**Figure 2:** Typical Transfer Characteristics



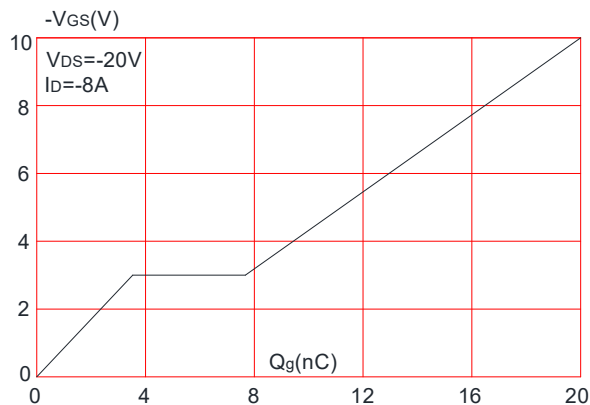
**Figure 3:** On-resistance vs. Drain Current



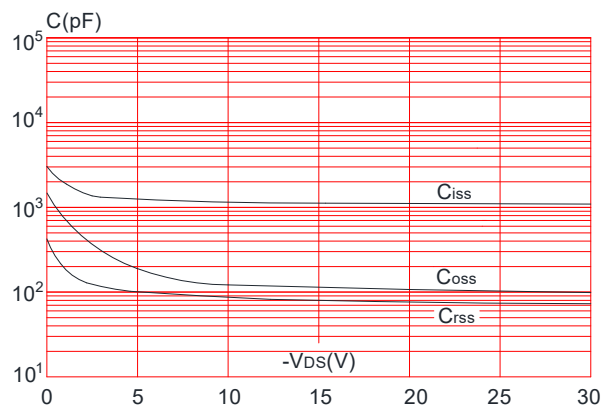
**Figure 4:** Body Diode Characteristics



**Figure 5:** Gate Charge Characteristics

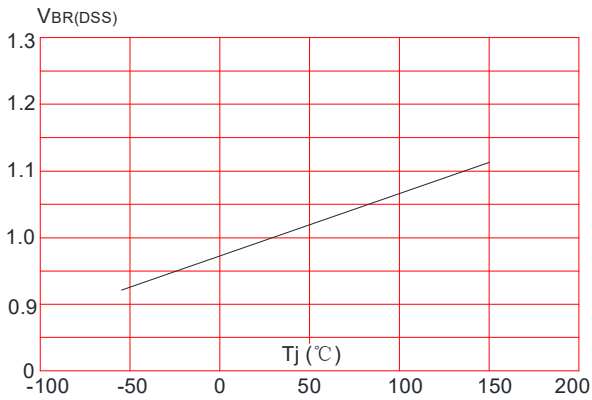


**Figure 6:** Capacitance Characteristics

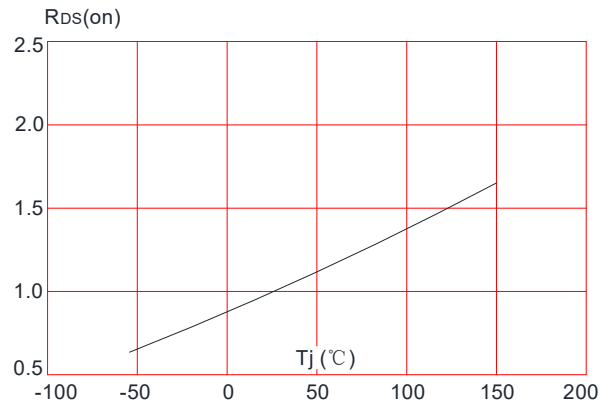




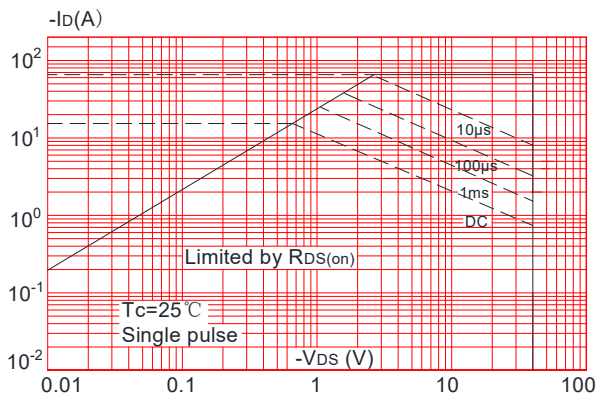
**Figure 7:** Normalized Breakdown Voltage vs. Junction Temperature



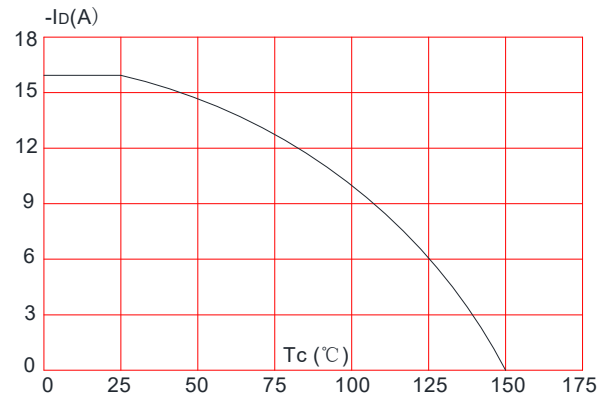
**Figure 8:** Normalized on Resistance vs. Junction Temperature



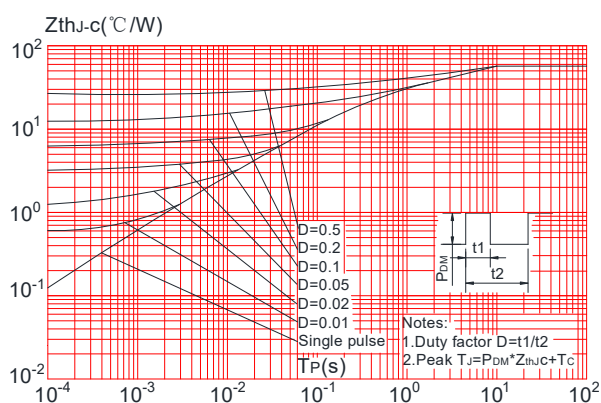
**Figure 9:** Maximum Safe Operating Area



**Figure 10:** Maximum Continuous Drain Current vs. Case Temperature



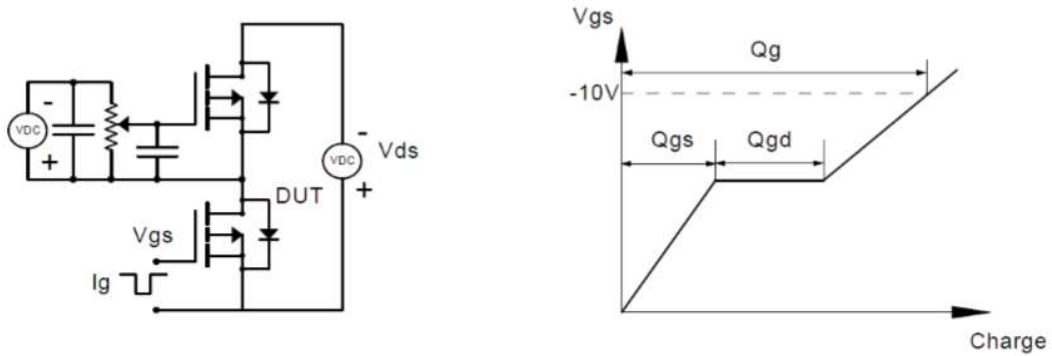
**Figure.11:** Maximum Effective Transient Thermal Impedance, Junction-to-Case



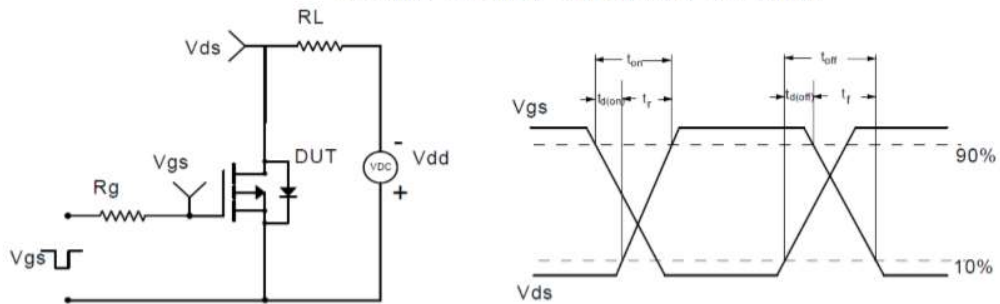


## Test Circuit-P

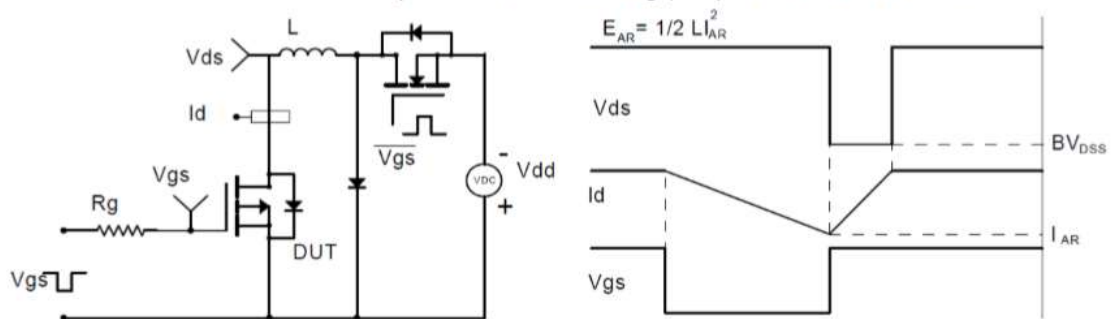
### Gate Charge Test Circuit & Waveform



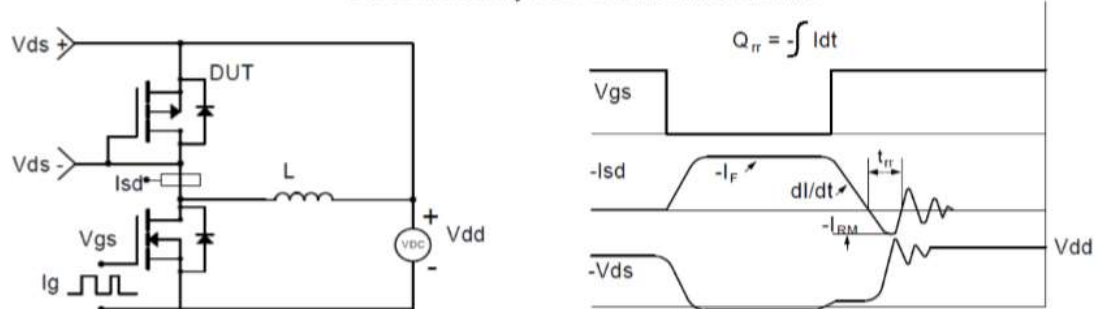
### Resistive Switching Test Circuit & Waveforms



### Unclamped Inductive Switching (UIS) Test Circuit & Waveforms

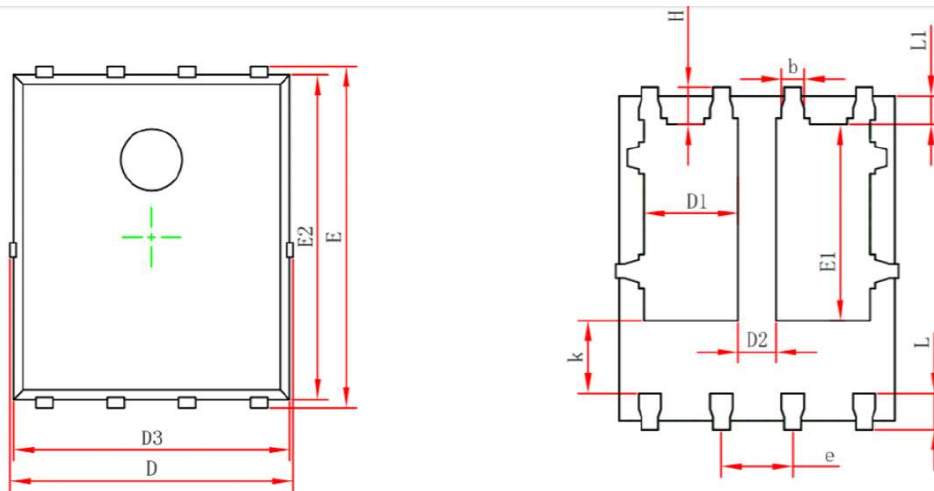


### Diode Recovery Test Circuit & Waveforms



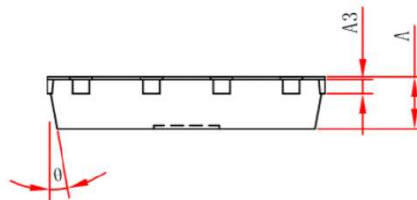


## Package Mechanical Data- PDFN5X6-8L



**Top View**

**Bottom View**



**Side View**


Symbol	Dimensions In Millimeters		Dimensions In Inches	
	Min.	Max.	Min.	Max.
A	0.900	1.000	0.035	0.039
A3	0.154REF.		0.006REF.	
D	4.944	5.096	0.195	0.201
E	5.974	6.126	0.235	0.241
D1	1.470	1.870	0.058	0.074
D2	0.470	0.870	0.019	0.034
E1	3.375	3.575	0.133	0.141
D3	4.824	4.976	0.190	0.196
E2	5.674	5.826	0.223	0.229
k	1.190	1.390	0.047	0.055
b	0.350	0.450	0.014	0.018
e	1.270TYP.		0.050TYP.	
L	0.559	0.711	0.022	0.028
L1	0.424	0.576	0.017	0.023
H	0.574	0.726	0.023	0.029
θ	10°	12°	10°	12°



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